

MARSHALL UNIVERSITY
GEOLOGY DEPARTMENT
RESEARCH EQUIPMENT

SAMPLE PREPARATION/ MINERAL SEPARATION



Spex Mill with tungsten carbide and agate balls for grinding rock samples

OTHER EQUIPMENT (SAMPLE PREPARATION)

- ✘ Rock crushing equipment
- ✘ Rock saws
- ✘ Rock grinding and polishing equipment
- ✘ Sieves; shaker
- ✘ Agate mortars and pestles



- Frantz Isodynamic separator
- Heavy liquids
- + separatory funnels
- Centrifuges; micro-filtration capabilities



MINERAL IDENTIFICATION

Three Research grade polarizing microscopes (Nikon Optiphot; Nikon 50i – POL; Meiji MT9900) with epi-illuminators for reflected light microscopy.





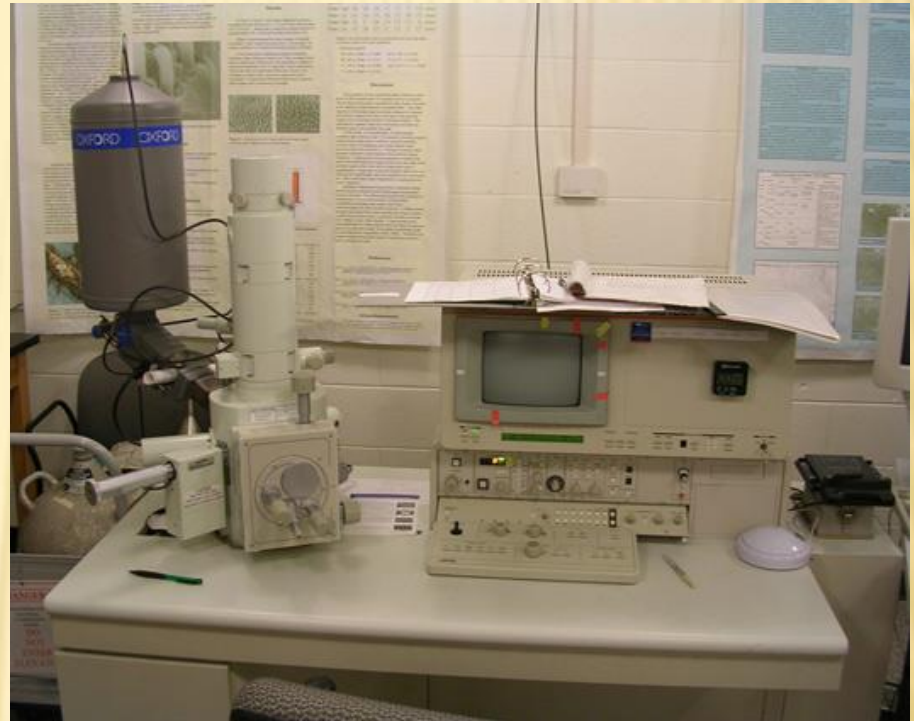
General Electric X-ray diffractometer (XRD-9000 Z-80/ XRD-6VS) & XRF Spectrometer (1960's model upgraded in 1986).

CHEMICAL ANALYSIS

I- Scanning electron microscope

Capable of:

- *imaging at magnifications up to 200,000 X.*
- *Qualitative analysis for all elements with atomic number higher than 8*
- *Quantitative analysis of spots in solids as small as 2 μm*



JSM-5310LV SEM with an Oxford Instruments EDS detector, and ISIS 300 software

CHEMICAL ANALYSIS

II- Varian Liberty 110 Inductively Coupled Atomic Emission Spectroscopy (ICP- OES)

Capabilities:

Useful for analysis of dilute solutions

*Elements (mostly metallic) are
detected at the parts per million
level (ppm).*



CHEMICAL ANALYSIS

III- Varian Spectra AA 600 Zeeman Graphite Furnace Atomic Absorption Spectrometer (GF-AAS)

Useful for the analysis of dilute aqueous solutions

Concentrations of cations detected at the part per billion (ppb) level .



CHEMICAL ANALYSIS

IV- Other equipment

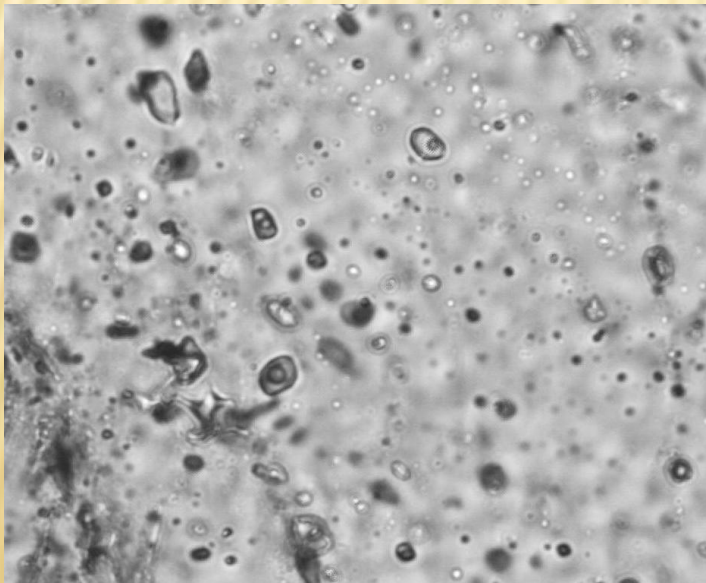
- Digital Titrators
- pH and conductivity meter



Acumet AR-50 pH and conductivity meter

FLUIDS IN MINERALS

Linkam THMS G600 heating – freezing stage for microthermometric studies of fluid inclusions in minerals



OTHER CAPABILITIES

The department also has access to:

- ✘ Hach Spectrophotometers
- ✘ Atomic Force Microscopy
- ✘ Transmission Electron microscopy
- ✘ Confocal Microscopy
- ✘ 3-D laser surface mapper